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Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	2566
Number of Logic Elements/Cells	25660
Total RAM Bits	1944576
Number of I/O	706
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1020-BBGA
Supplier Device Package	1020-FBGA (33x33)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep1s25f1020c6n

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Section I. Stratix Device Family Data Sheet

This section provides the data sheet specifications for Stratix® devices. They contain feature definitions of the internal architecture, configuration and JTAG boundary-scan testing information, DC operating conditions, AC timing parameters, a reference to power consumption, and ordering information for Stratix devices.

This section contains the following chapters:

- Chapter 1, Introduction
- Chapter 2, Stratix Architecture
- Chapter 3, Configuration & Testing
- Chapter 4, DC & Switching Characteristics
- Chapter 5, Reference & Ordering Information

Revision History

The table below shows the revision history for Chapters 1 through 5.

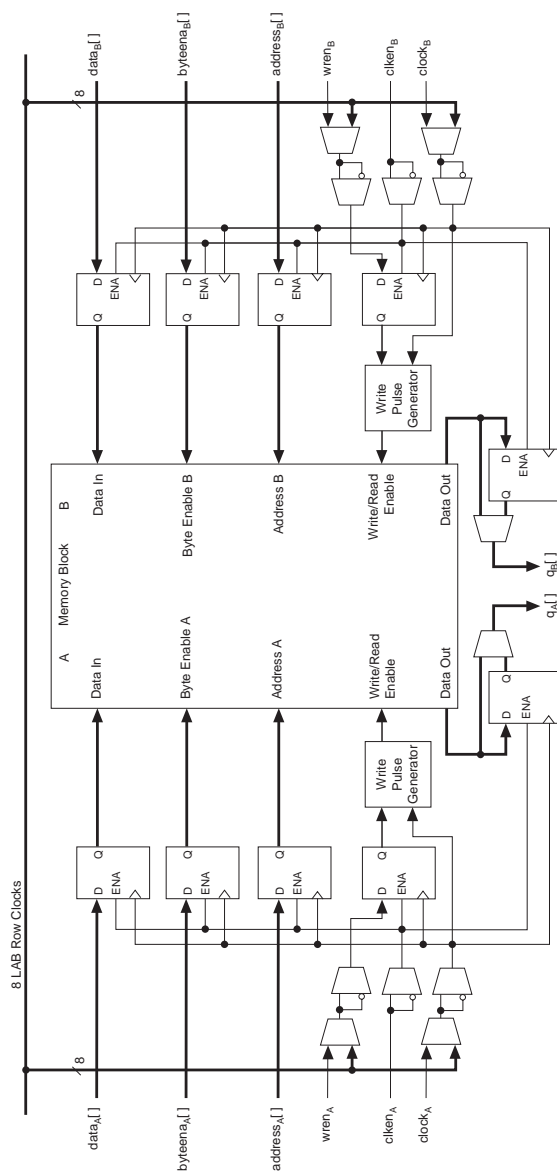
Chapter	Date/Version	Changes Made
1	July 2005, v3.2	● Minor content changes.
	September 2004, v3.1	● Updated Table 1–6 on page 1–5.
	April 2004, v3.0	● Main section page numbers changed on first page. ● Changed PCI-X to PCI-X 1.0 in “Features” on page 1–2. ● Global change from SignalTap to SignalTap II. ● The DSP blocks in “Features” on page 1–2 provide dedicated implementation of multipliers that are now “faster than 300 MHz.”
	January 2004, v2.2	● Updated -5 speed grade device information in Table 1-6.
	October 2003, v2.1	● Add -8 speed grade device information.
	July 2003, v2.0	● Format changes throughout chapter.

Chapter	Date/Version	Changes Made
4		<ul style="list-style-type: none"> Updated Table 4–123 on page 4–85 through Table 4–126 on page 4–92. Updated Note 3 in Table 4–123 on page 4–85. Table 4–125 on page 4–88: moved to correct order in chapter, and updated table. Updated Table 4–126 on page 4–92. Updated Table 4–127 on page 4–94. Updated Table 4–128 on page 4–95.
	April 2004, v3.0	<ul style="list-style-type: none"> Table 4–129 on page 4–96: updated table and added Note 10. Updated Table 4–131 and Table 4–132 on page 4–100. Updated Table 4–110 on page 4–74. Updated Table 4–123 on page 4–85. Updated Table 4–124 on page 4–87. through Table 4–126 on page 4–92. Added Note 10 to Table 4–129 on page 4–96. Moved Table 4–127 on page 4–94 to correct order in the chapter. Updated Table 4–131 on page 4–100 through Table 4–132 on page 4–100. Deleted t_{XZ} and t_{ZX} from Figure 4–4. Waveform was added to Figure 4–6. The minimum and maximum duty cycle values in Note 3 of Table 4–8 were moved to a new Table 4–9. Changes were made to values in SSTL-3 Class I and II rows in Table 4–17. Note 1 was added to Table 4–34. Added t_{SU_R} and t_{SU_C} rows in Table 4–38. Changed Table 4–55 title from “EP1S10 Column Pin Fast Regional Clock External I/O Timing Parameters” to “EP1S10 External I/O Timing on Column Pins Using Fast Regional Clock Networks.” Changed values in Tables 4–46, 4–48 to 4–51, 4–128, and 4–131. Added t_{ARESET} row in Tables 4–127 to 4–132. Deleted -5 Speed Grade column in Tables 4–117 to 4–119 and 4–122 to 4–123. Fixed differential waveform in Figure 4–1. Added “Definition of I/O Skew” section. Added t_{SU} and t_{CO_C} rows and made changes to values in t_{PRE} and t_{CLKHL} rows in Table 4–46. Values changed in the t_{SU} and t_H rows in Table 4–47. Values changed in the $t_{M4KCLKHL}$ row in Table 4–49. Values changed in the $t_{MRAMCLKHL}$ row in Table 4–50. Added Table 4–51 to “Internal Timing Parameters” section. The timing information is preliminary in Tables 4–55 through 4–96. Table 4–111 was separated into 3 tables: Tables 4–111 to 4–113.
	November 2003, v2.2	<ul style="list-style-type: none"> Updated Tables 4–127 through 4–129.

TriMatrix Memory

TriMatrix memory consists of three types of RAM blocks: M512, M4K, and M-RAM blocks. Although these memory blocks are different, they can all implement various types of memory with or without parity, including true dual-port, simple dual-port, and single-port RAM, ROM, and FIFO buffers. Table 2–3 shows the size and features of the different RAM blocks.

Table 2–3. TriMatrix Memory Features (Part 1 of 2)			
Memory Feature	M512 RAM Block (32 × 18 Bits)	M4K RAM Block (128 × 36 Bits)	M-RAM Block (4K × 144 Bits)
Maximum performance	(1)	(1)	(1)
True dual-port memory		✓	✓
Simple dual-port memory	✓	✓	✓
Single-port memory	✓	✓	✓
Shift register	✓	✓	
ROM	✓	✓	(2)
FIFO buffer	✓	✓	✓
Byte enable		✓	✓
Parity bits	✓	✓	✓
Mixed clock mode	✓	✓	✓
Memory initialization	✓	✓	
Simple dual-port memory mixed width support	✓	✓	✓
True dual-port memory mixed width support		✓	✓
Power-up conditions	Outputs cleared	Outputs cleared	Outputs unknown
Register clears	Input and output registers	Input and output registers	Output registers
Mixed-port read-during-write	Unknown output/old data	Unknown output/old data	Unknown output

Figure 2–24. Independent Clock Mode *Notes (1), (2)***Notes to Figure 2–24**

- (1) All registers shown have asynchronous clear ports.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

Table 2–13 shows the number of DSP blocks in each Stratix device.

Table 2–13. DSP Blocks in Stratix Devices <i>Notes (1), (2)</i>				
Device	DSP Blocks	Total 9×9 Multipliers	Total 18×18 Multipliers	Total 36×36 Multipliers
EP1S10	6	48	24	6
EP1S20	10	80	40	10
EP1S25	10	80	40	10
EP1S30	12	96	48	12
EP1S40	14	112	56	14
EP1S60	18	144	72	18
EP1S80	22	176	88	22

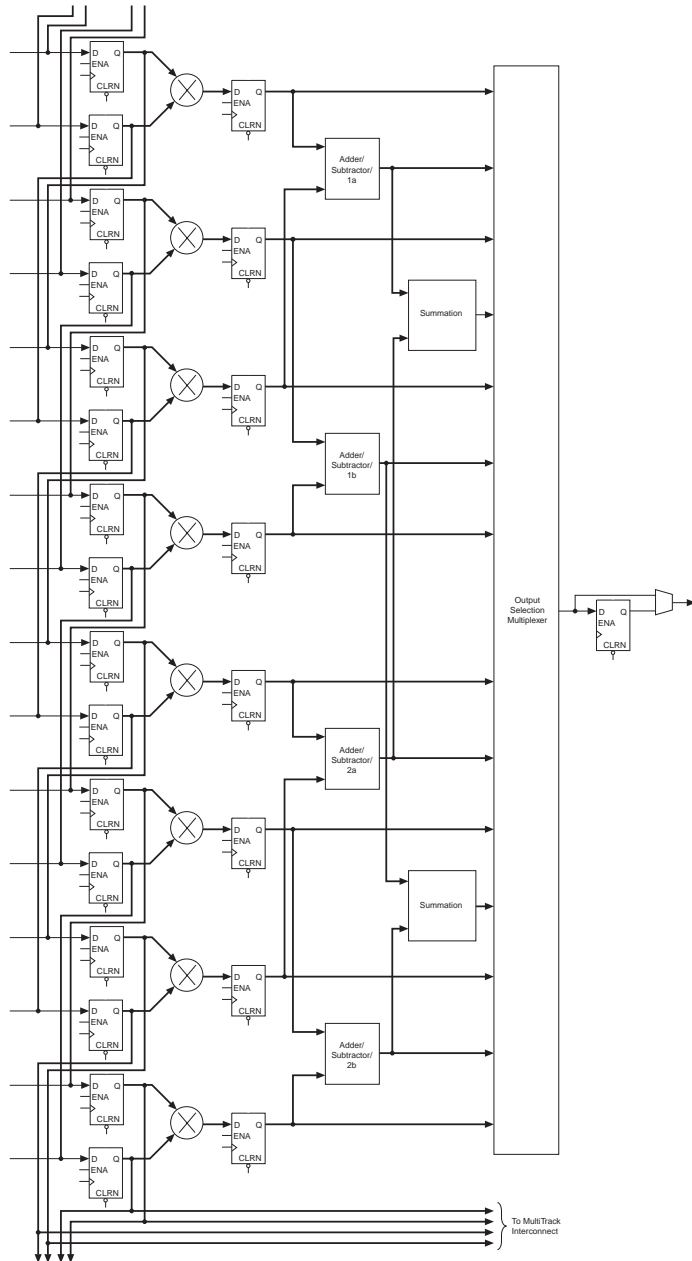
Notes to Table 2–13:

- (1) Each device has either the number of 9×9 -, 18×18 -, or 36×36 -bit multipliers shown. The total number of multipliers for each device is not the sum of all the multipliers.
- (2) The number of supported multiply functions shown is based on signed/signed or unsigned/unsigned implementations.

DSP block multipliers can optionally feed an adder/subtractor or accumulator within the block depending on the configuration. This makes routing to LEs easier, saves LE routing resources, and increases performance, because all connections and blocks are within the DSP block. Additionally, the DSP block input registers can efficiently implement shift registers for FIR filter applications.

Figure 2–30 shows the top-level diagram of the DSP block configured for 18×18 -bit multiplier mode. Figure 2–31 shows the 9×9 -bit multiplier configuration of the DSP block.

Figure 2–31. DSP Block Diagram for 9×9 -Bit Configuration



Output Selection Multiplexer

The outputs from the various elements of the adder/output block are routed through an output selection multiplexer. Based on the DSP block operational mode and user settings, the multiplexer selects whether the output from the multiplier, the adder/subtractor/accumulator, or summation block feeds to the output.

Output Registers

Optional output registers for the DSP block outputs are controlled by four sets of control signals: `clock [3..0]`, `ac1r [3..0]`, and `ena [3..0]`. Output registers can be used in any mode.

Modes of Operation

The adder, subtractor, and accumulate functions of a DSP block have four modes of operation:

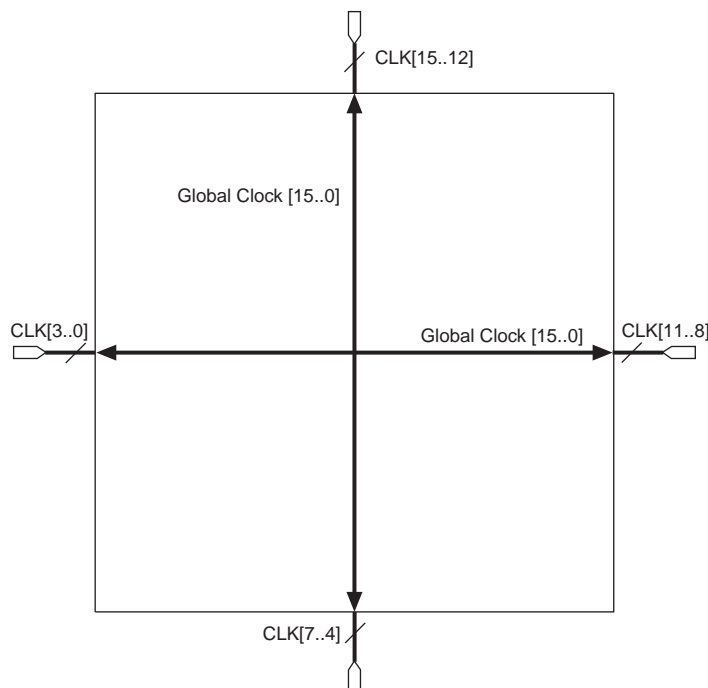
- Simple multiplier
- Multiply-accumulator
- Two-multipliers adder
- Four-multipliers adder



Each DSP block can only support one mode. Mixed modes in the same DSP block is not supported.

Simple Multiplier Mode

In simple multiplier mode, the DSP block drives the multiplier sub-block result directly to the output with or without an output register. Up to four 18×18 -bit multipliers or eight 9×9 -bit multipliers can drive their results directly out of one DSP block. See [Figure 2-35](#).

Figure 2–42. Global Clock *Note (1)***Note to Figure 2–42:**

- (1) The corner fast PLLs can also be driven through the global or regional clock networks. The global or regional clock input to the fast PLL can be driven by an output from another PLL, a pin-driven global or regional clock, or internally-generated global signals.

Regional Clock Network

There are four regional clock networks within each quadrant of the Stratix device that are driven by the same dedicated $\text{CLK}[15..0]$ input pins or from PLL outputs. From a top view of the silicon, $\text{RCLK}[0..3]$ are in the top left quadrant, $\text{RCLK}[8..11]$ are in the top-right quadrant, $\text{RCLK}[4..7]$ are in the bottom-left quadrant, and $\text{RCLK}[12..15]$ are in the bottom-right quadrant. The regional clock networks only pertain to the quadrant they drive into. The regional clock networks provide the lowest clock delay and skew for logic contained within a single quadrant. RCLK cannot be driven by internal logic. The CLK clock pins symmetrically drive the RCLK networks within a particular quadrant, as shown in Figure 2–43. See Figures 2–50 and 2–51 for RCLK connections from PLLs and CLK pins.

Table 2–22. Fast PLL Port I/O Standards (Part 2 of 2)

I/O Standard	Input	
	INCLK	PLENABLE
SSTL-2 Class II	✓	
SSTL-3 Class I	✓	
SSTL-3 Class II	✓	
AGP (1× and 2×)		
CTT	✓	

Table 2–23 shows the performance on each of the fast PLL clock inputs when using LVDS, LVPECL, 3.3-V PCML, or HyperTransport technology.

Table 2–23. LVDS Performance on Fast PLL Input

Fast PLL Clock Input	Maximum Input Frequency (MHz)
CLK0, CLK2, CLK9, CLK11, FPLL7CLK, FPLL8CLK, FPLL9CLK, FPLL10CLK	717 ⁽¹⁾
CLK1, CLK3, CLK8, CLK10	645

Note to Table 2–23:

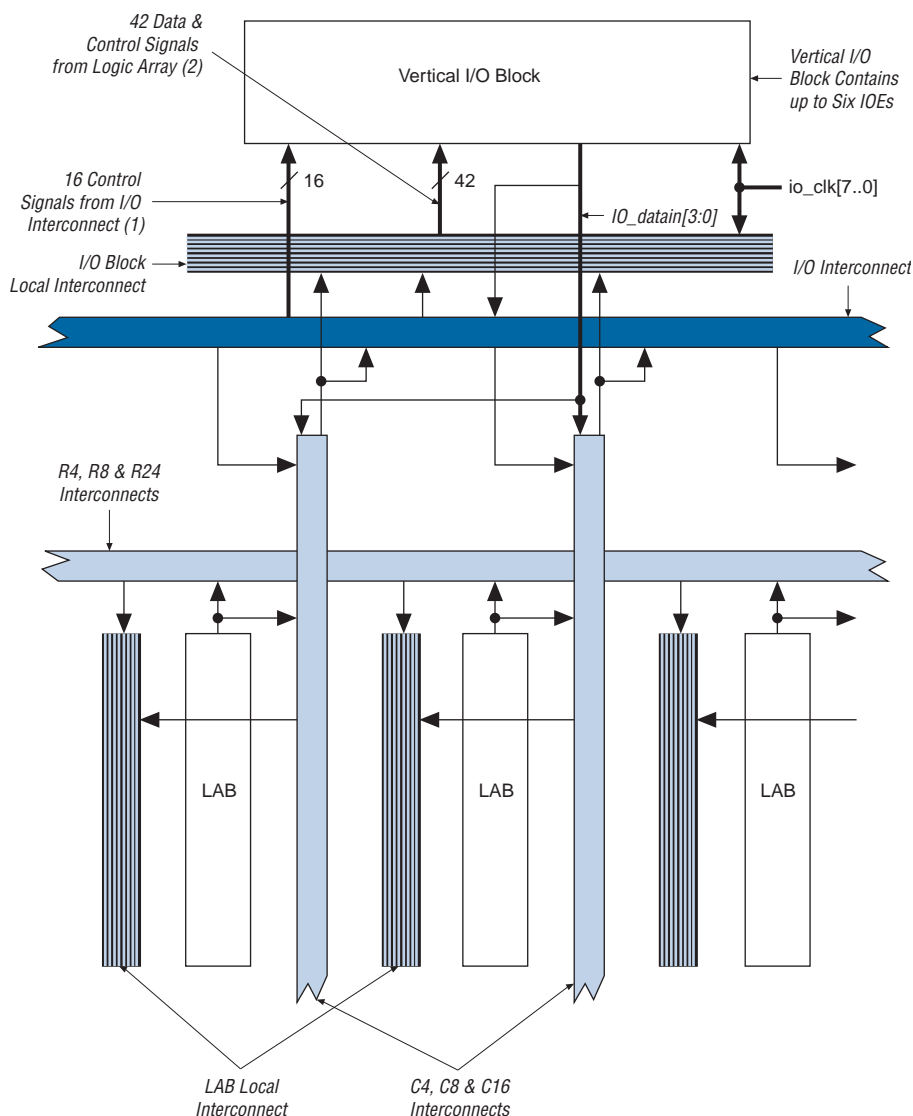
- (1) See the chapter *DC & Switching Characteristics* of the *Stratix Device Handbook, Volume 1* for more information.

External Clock Outputs

Each fast PLL supports differential or single-ended outputs for source-synchronous transmitters or for general-purpose external clocks. There are no dedicated external clock output pins. Any I/O pin can be driven by the fast PLL global or regional outputs as an external output pin. The I/O standards supported by any particular bank determines what standards are possible for an external clock output driven by the fast PLL in that bank.

Phase Shifting

Stratix device fast PLLs have advanced clock shift capability that enables programmable phase shifts. You can enter a phase shift (in degrees or time units) for each PLL clock output port or for all outputs together in one shift. You can perform phase shifting in time units with a resolution range of 125 to 416.66 ps. This resolution is a function of the VCO period, with the finest step being equal to an eighth (×0.125) of the VCO period.

Figure 2–61. Column I/O Block Connection to the Interconnect**Notes to Figure 2–61:**

- (1) The 16 control signals are composed of four output enables `io_boe[3..0]`, four clock enables `io_bce[3..0]`, four clocks `io_bclk[3..0]`, and four clear signals `io_bclr[3..0]`.
- (2) The 42 data and control signals consist of 12 data out lines; six lines each for DDR applications `io_dataouta[5..0]` and `io_dataoutb[5..0]`, six output enables `io_coe[5..0]`, six input clock enables `io_cce_in[5..0]`, six output clock enables `io_cce_out[5..0]`, six clocks `io_cclk[5..0]`, and six clear signals `io_cclr[5..0]`.

I/O pin has an individual slew-rate control, allowing you to specify the slew rate on a pin-by-pin basis. The slew-rate control affects both the rising and falling edges.

Bus Hold

Each Stratix device I/O pin provides an optional bus-hold feature. The bus-hold circuitry can weakly hold the signal on an I/O pin at its last-driven state. Since the bus-hold feature holds the last-driven state of the pin until the next input signal is present, an external pull-up or pull-down resistor is not needed to hold a signal level when the bus is tri-stated.

Table 2–29 shows bus hold support for different pin types.

Table 2–29. Bus Hold Support	
Pin Type	Bus Hold
I/O pins	✓
CLK [15 . . 0]	
CLK [0, 1, 2, 3, 8, 9, 10, 11]	
FCLK	✓
FPLL [7 . . 10] CLK	

The bus-hold circuitry also pulls undriven pins away from the input threshold voltage where noise can cause unintended high-frequency switching. You can select this feature individually for each I/O pin. The bus-hold output drives no higher than V_{CCIO} to prevent overdriving signals. If the bus-hold feature is enabled, the programmable pull-up option cannot be used. Disable the bus-hold feature when using open-drain outputs with the GTL+ I/O standard or when the I/O pin has been configured for differential signals.

The bus-hold circuitry uses a resistor with a nominal resistance (R_{BH}) of approximately 7 k Ω to weakly pull the signal level to the last-driven state. See the *DC & Switching Characteristics* chapter of the *Stratix Device Handbook, Volume 1* for the specific sustaining current driven through this resistor and overdrive current used to identify the next-driven input level. This information is provided for each V_{CCIO} voltage level.

The bus-hold circuitry is active only after configuration. When going into user mode, the bus-hold circuit captures the value on the pin present at the end of configuration.

Table 2–37. EP1S10, EP1S20 & EP1S25 Device Differential Channels (Part 2 of 2) *Note (1)*

Device	Package	Transmitter/ Receiver	Total Channels	Maximum Speed (Mbps)	Center Fast PLLs			
					PLL 1	PLL 2	PLL 3	PLL 4
EP1S25	672-pin FineLine BGA 672-pin BGA	Transmitter (2)	56	624 (4)	14	14	14	14
				624 (3)	28	28	28	28
		Receiver	58	624 (4)	14	15	15	14
				624 (3)	29	29	29	29
	780-pin FineLine BGA	Transmitter (2)	70	840 (4)	18	17	17	18
				840 (3)	35	35	35	35
		Receiver	66	840 (4)	17	16	16	17
				840 (3)	33	33	33	33
	1,020-pin FineLine BGA	Transmitter (2)	78	840 (4)	19	20	20	19
				840 (3)	39	39	39	39
		Receiver	78	840 (4)	19	20	20	19
				840 (3)	39	39	39	39

Notes to Table 2–37:

- (1) The first row for each transmitter or receiver reports the number of channels driven directly by the PLL. The second row below it shows the maximum channels a PLL can drive if cross bank channels are used from the adjacent center PLL. For example, in the 484-pin FineLine BGA EP1S10 device, PLL 1 can drive a maximum of five channels at 840 Mbps or a maximum of 10 channels at 840 Mbps. The Quartus II software may also merge receiver and transmitter PLLs when a receiver is driving a transmitter. In this case, one fast PLL can drive both the maximum numbers of receiver and transmitter channels.
- (2) The number of channels listed includes the transmitter clock output (tx_outclock) channel. If the design requires a DDR clock, it can use an extra data channel.
- (3) These channels span across two I/O banks per side of the device. When a center PLL clocks channels in the opposite bank on the same side of the device it is called cross-bank PLL support. Both center PLLs can clock cross-bank channels simultaneously if, for example, PLL_1 is clocking all receiver channels and PLL_2 is clocking all transmitter channels. You cannot have two adjacent PLLs simultaneously clocking cross-bank receiver channels or two adjacent PLLs simultaneously clocking transmitter channels. Cross-bank allows for all receiver channels on one side of the device to be clocked on one clock while all transmitter channels on the device are clocked on the other center PLL. Crossbank PLLs are supported at full-speed, 840 Mbps. For wire-bond devices, the full-speed is 624 Mbps.
- (4) These values show the channels available for each PLL without crossing another bank.

When you span two I/O banks using cross-bank support, you can route only two load enable signals total between the PLLs. When you enable rx_data_align, you use both rxloadena and txloadena of a PLL. That leaves no loadena for the second PLL.

Table 2–41. EP1S80 Differential Channels (Part 2 of 2) Note (1)

Package	Transmitter/ Receiver	Total Channels	Maximum Speed (Mbps)	Center Fast PLLs				Corner Fast PLLs (2), (3)			
				PLL1	PLL2	PLL3	PLL4	PLL7	PLL8	PLL9	PLL10
1,508-pin FineLine BGA	Transmitter (4)	80 (72) (7)	840	10 (10)	10 (10)	10 (10)	10 (10)	20 (8)	20 (8)	20 (8)	20 (8)
			840 (5),(8)	20 (20)	20 (20)	20 (20)	20 (20)	20 (8)	20 (8)	20 (8)	20 (8)
	Receiver	80 (56) (7)	840	20	20	20	20	10 (14)	10 (14)	10 (14)	10 (14)
			840 (5),(8)	40	40	40	40	10 (14)	10 (14)	10 (14)	10 (14)

Notes to Tables 2–38 through 2–41:

- (1) The first row for each transmitter or receiver reports the number of channels driven directly by the PLL. The second row below it shows the maximum channels a PLL can drive if cross bank channels are used from the adjacent center PLL. For example, in the 780-pin FineLine BGA EP1S30 device, PLL 1 can drive a maximum of 18 transmitter channels at 840 Mbps or a maximum of 35 transmitter channels at 840 Mbps. The Quartus II software may also merge transmitter and receiver PLLs when a receiver is driving a transmitter. In this case, one fast PLL can drive both the maximum numbers of receiver and transmitter channels.
- (2) Some of the channels accessible by the center fast PLL and the channels accessible by the corner fast PLL overlap. Therefore, the total number of channels is not the addition of the number of channels accessible by PLLs 1, 2, 3, and 4 with the number of channels accessible by PLLs 7, 8, 9, and 10. For more information on which channels overlap, see the Stratix device pin-outs at www.altera.com.
- (3) The corner fast PLLs in this device support a data rate of 840 Mbps for channels labeled “high” speed in the device pin-outs at www.altera.com.
- (4) The numbers of channels listed include the transmitter clock output (tx_outclock) channel. An extra data channel can be used if a DDR clock is needed.
- (5) These channels span across two I/O banks per side of the device. When a center PLL clocks channels in the opposite bank on the same side of the device it is called cross-bank PLL support. Both center PLLs can clock cross-bank channels simultaneously if say PLL_1 is clocking all receiver channels and PLL_2 is clocking all transmitter channels. You cannot have two adjacent PLLs simultaneously clocking cross-bank receiver channels or two adjacent PLLs simultaneously clocking transmitter channels. Cross-bank allows for all receiver channels on one side of the device to be clocked on one clock while all transmitter channels on the device are clocked on the other center PLL. Crossbank PLLs are supported at full-speed, 840 Mbps. For wire-bond devices, the full-speed is 624 Mbps.
- (6) PLLs 7, 8, 9, and 10 are not available in this device.
- (7) The number in parentheses is the number of slow-speed channels, guaranteed to operate at up to 462 Mbps. These channels are independent of the high-speed differential channels. For the location of these channels, see the device pin-outs at www.altera.com.
- (8) See the Stratix device pin-outs at www.altera.com. Channels marked “high” speed are 840 MBps and “low” speed channels are 462 MBps.

The high-speed differential I/O circuitry supports the following high speed I/O interconnect standards and applications:

- UTOPIA IV
- SPI-4 Phase 2 (POS-PHY Level 4)
- SFI-4
- 10G Ethernet XSBI

The Stratix device instruction register length is 10 bits and the USERCODE register length is 32 bits. Tables 3–2 and 3–3 show the boundary-scan register length and device IDCODE information for Stratix devices.

Table 3–2. Stratix Boundary-Scan Register Length

Device	Boundary-Scan Register Length
EP1S10	1,317
EP1S20	1,797
EP1S25	2,157
EP1S30	2,253
EP1S40	2,529
EP1S60	3,129
EP1S80	3,777

Table 3–3. 32-Bit Stratix Device IDCODE

Device	IDCODE (32 Bits) (1)			
	Version (4 Bits)	Part Number (16 Bits)	Manufacturer Identity (11 Bits)	LSB (1 Bit) (2)
EP1S10	0000	0010 0000 0000 0001	000 0110 1110	1
EP1S20	0000	0010 0000 0000 0010	000 0110 1110	1
EP1S25	0000	0010 0000 0000 0011	000 0110 1110	1
EP1S30	0000	0010 0000 0000 0100	000 0110 1110	1
EP1S40	0000	0010 0000 0000 0101	000 0110 1110	1
EP1S60	0000	0010 0000 0000 0110	000 0110 1110	1
EP1S80	0000	0010 0000 0000 0111	000 0110 1110	1

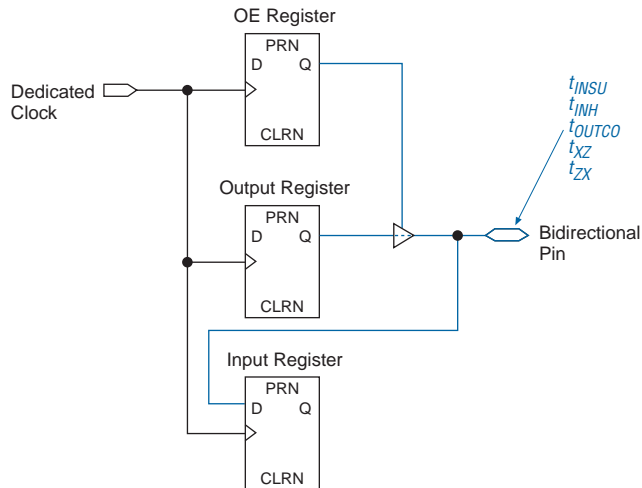
Notes to Tables 3–2 and 3–3:

- (1) The most significant bit (MSB) is on the left.
- (2) The IDCODE's least significant bit (LSB) is always 1.

External Timing Parameters

External timing parameters are specified by device density and speed grade. Figure 4-4 shows the pin-to-pin timing model for bidirectional IOE pin timing. All registers are within the IOE.

Figure 4-4. External Timing in Stratix Devices



All external timing parameters reported in this section are defined with respect to the dedicated clock pin as the starting point. All external I/O timing parameters shown are for 3.3-V LVTTL I/O standard with the 24-mA current strength and fast slew rate. For external I/O timing using standards other than LVTTL or for different current strengths, use the I/O standard input and output delay adders in Tables 4-103 through 4-108.

Table 4–71. EP1S25 External I/O Timing on Row Pins Using Regional Clock Networks

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{INSU}	1.793		1.927		2.182		2.542		ns
t_{INH}	0.000		0.000		0.000		0.000		ns
t_{OUTCO}	2.759	5.457	2.759	5.835	2.759	6.346	2.759	7.024	ns
t_{XZ}	2.786	5.511	2.786	5.891	2.786	6.414	2.786	7.106	ns
t_{ZX}	2.786	5.511	2.786	5.891	2.786	6.414	2.786	7.106	ns
t_{INSUPLL}	1.169		1.221		1.373		1.600		ns
t_{INHPLL}	0.000		0.000		0.000		0.000		ns
t_{OUTCOPLL}	1.375	2.861	1.375	2.999	1.375	3.082	1.375	3.174	ns
t_{XZPLL}	1.402	2.915	1.402	3.055	1.402	3.150	1.402	3.256	ns
t_{ZXPLL}	1.402	2.915	1.402	3.055	1.402	3.150	1.402	3.256	ns

Table 4–72. EP1S25 External I/O Timing on Row Pins Using Global Clock Networks

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{INSU}	1.665		1.779		2.012		2.372		ns
t_{INH}	0.000		0.000		0.000		0.000		ns
t_{OUTCO}	2.834	5.585	2.834	5.983	2.834	6.516	2.834	7.194	ns
t_{XZ}	2.861	5.639	2.861	6.039	2.861	6.584	2.861	7.276	ns
t_{ZX}	2.861	5.639	2.861	6.039	2.861	6.584	2.861	7.276	ns
t_{INSUPLL}	1.538		1.606		1.816		2.121		ns
t_{INHPLL}	0.000		0.000		0.000		0.000		ns
t_{OUTCOPLL}	1.164	2.492	1.164	2.614	1.164	2.639	1.164	2.653	ns
t_{XZPLL}	1.191	2.546	1.191	2.670	1.191	2.707	1.191	2.735	ns
t_{ZXPLL}	1.191	2.546	1.191	2.670	1.191	2.707	1.191	2.735	ns

Tables 4–85 through 4–90 show the external timing parameters on column and row pins for EP1S60 devices.

Table 4–85. EP1S60 External I/O Timing on Column Pins Using Fast Regional Clock Networks *Note (1)*

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{INSU}	3.029		3.277		3.733		NA		ns
t_{INH}	0.000		0.000		0.000		NA		ns
t_{OUTCO}	2.446	4.871	2.446	5.215	2.446	5.685	NA	NA	ns
t_{xZ}	2.386	4.745	2.386	5.083	2.386	5.561	NA	NA	ns
t_{ZX}	2.386	4.745	2.386	5.083	2.386	5.561	NA	NA	ns

Table 4–86. EP1S60 External I/O Timing on Column Pins Using Regional Clock Networks *Note (1)*

Parameter	-5 Speed Grade		-6 Speed Grade		-7 Speed Grade		-8 Speed Grade		Unit
	Min	Max	Min	Max	Min	Max	Min	Max	
t_{INSU}	2.491		2.691		3.060		NA		ns
t_{INH}	0.000		0.000		0.000		NA		ns
t_{OUTCO}	2.767	5.409	2.767	5.801	2.767	6.358	NA	NA	ns
t_{xZ}	2.707	5.283	2.707	5.669	2.707	6.234	NA	NA	ns
t_{ZX}	2.707	5.283	2.707	5.669	2.707	6.234	NA	NA	ns
t_{INSUPLL}	1.233		1.270		1.438		NA		ns
t_{INHPLL}	0.000		0.000		0.000		NA		ns
t_{OUTCOPLL}	1.078	2.278	1.078	2.395	1.078	2.428	NA	NA	ns
t_{xZPLL}	1.018	2.152	1.018	2.263	1.018	2.304	NA	NA	ns
t_{ZXPLL}	1.018	2.152	1.018	2.263	1.018	2.304	NA	NA	ns

Table 4–125. High-Speed I/O Specifications for Flip-Chip Packages (Part 2 of 4) Notes (1), (2)														
Symbol	Conditions	-5 Speed Grade			-6 Speed Grade			-7 Speed Grade			-8 Speed Grade			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
f_{HCLK} (Clock frequency) (PCML) $f_{\text{HCLK}} = f_{\text{HSDR}} / W$	$W = 4$ to 30 (Serdes used)	10		100	10		100	10		77.75	10		77.75	MHz
	$W = 2$ (Serdes bypass)	50		200	50		200	50		150	50		150	MHz
	$W = 2$ (Serdes used)	150		200	150		200	150		155.5	150		155.5	MHz
	$W = 1$ (Serdes bypass)	100		250	100		250	100		200	100		200	MHz
	$W = 1$ (Serdes used)	300		400	300		400	300		311	300		311	MHz
f_{HSDR} Device operation (PCML)	$J = 10$	300		400	300		400	300		311	300		311	Mbps
	$J = 8$	300		400	300		400	300		311	300		311	Mbps
	$J = 7$	300		400	300		400	300		311	300		311	Mbps
	$J = 4$	300		400	300		400	300		311	300		311	Mbps
	$J = 2$	100		400	100		400	100		300	100		300	Mbps
	$J = 1$	100		250	100		250	100		200	100		200	Mbps
TCCS	All			200			200			300			300	ps

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